FAIRCHILD SEMICONDUCTOR™

December 2001
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74ALVC16839
Low Voltage 20-Bit Selectable Register/Buffer with 3.6V Tolerant Inputs and Outputs

General Description

The ALVC16839 contains twenty non-inverting selectable buffered or registered paths. The device can be configured to operate in a registered, or flow through buffer mode by utilizing the register enable (REGE) and Clock (CLK) signals. The device operates in a 20-bit word wide mode. All outputs can be placed into 3-STATE through use of the $\overline{OE}$ pin. These devices are ideally suited for buffered or registered 168 pin and 200 pin SDRAM DIMM memory modules.

The 74ALVC16839 is designed for low voltage (1.65V to 3.6V) V_{CC} applications with I/O compatibility up to 3.6V.

The 74ALVC16839 is fabricated with an advanced CMOS technology to achieve high speed operation while maintaining low CMOS power dissipation.

Features

- Compatible with PC100 and PC133 DIMM module specifications
- 1.65V to 3.6V V_{CC} supply operation
- 3.6V tolerant inputs and outputs
- t_{PD} (CLK to O_n)
  - 3.7 ns max for 3.0V to 3.6V V_{CC}
  - 4.9 ns max for 2.3V to 2.7V V_{CC}
  - 8.8 ns max for 1.65V to 1.95V V_{CC}
- Power-off high impedance inputs and outputs
- Supports live insertion and withdrawal (Note 1)
- Uses patented noise/EMI reduction circuitry
- Latchup conforms to JEDEC JED78
- ESD performance:
  - Human body model > 2000V
  - Machine model > 200V

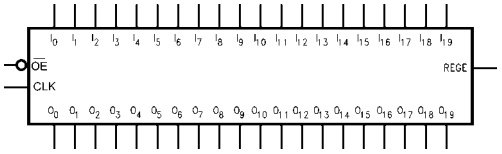
Note 1: To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pull-up resistor; the minimum value of the resistor is determined by the current-sourcing capability of the driver.

Ordering Code:

Order Number	Package Number	Package Descriptions
74ALVC16839MTD	MTD56	56-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 6.1mm Wide

Devices also available in Tape and Reel. Specify by appending suffix letter "X" to the ordering code.

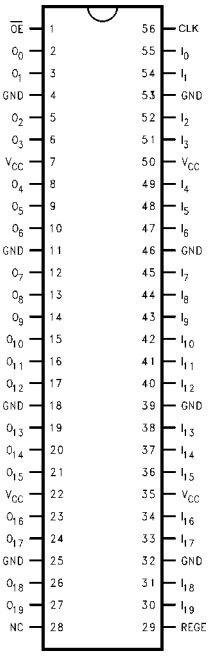
Logic Symbol



Pin Descriptions

Pin Names	Description
$\overline{OE}$	Output Enable Input (Active LOW)
I_0–I_{19}	Inputs
O_0–O_{19}	Outputs
CLK	Clock Input
REGE	Register Enable Input

Connection Diagram



Truth Table

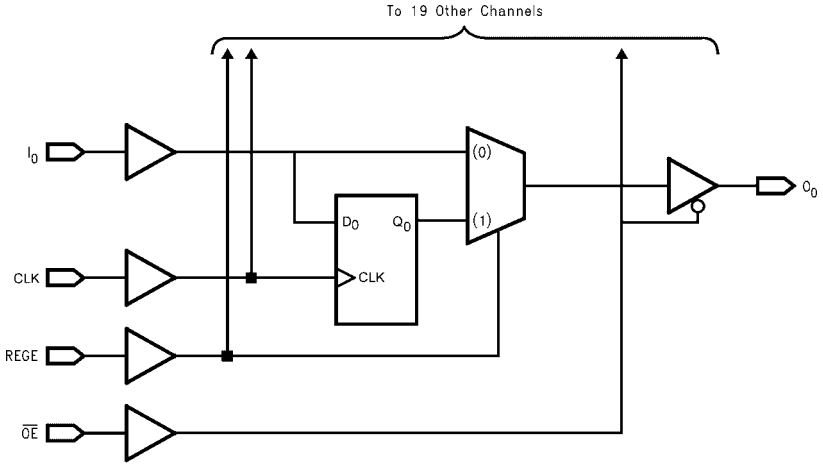
Inputs				Outputs
CLK	REGE	I_n	$\overline{OE}$	O_n
↑	H	H	L	H
↑	H	L	L	L
X	L	H	L	H
X	L	L	L	L
X	X	X	H	Z

H = Logic HIGH
L = Logic LOW
X = Don't Care, but not floating
Z = High Impedance
↑ = LOW-to-HIGH Clock Transition

Functional Description

The 74ALVC16839 consists of twenty selectable non-inverting buffers or registers with word wide modes. Mode functionality is selected through operation of the CLK and REGE pin as shown by the truth table. When REGE is held at a logic HIGH the device operates as a 20-bit register. Data is transferred from I_n to O_n on the rising edge of the CLK input. When the REGE pin is held at a logic LOW the device operates in a flow through mode and data propagates directly from the I_n to the O_n outputs. All outputs can be 3-stated by holding the $\overline{OE}$ pin at a logic HIGH.

Logic Diagram



Absolute Maximum Ratings (Note 2)

Supply Voltage (V_{CC})	−0.5V to +4.6V
DC Input Voltage (V_I)	−0.5V to 4.6V
Output Voltage (V_O) (Note 3)	−0.5V to V_{CC} +0.5V
DC Input Diode Current (I_{IK})	
V_I < 0V	−50 mA
DC Output Diode Current (I_{OK})	
V_O < 0V	−50 mA
DC Output Source/Sink Current	
(I_{OH}/I_{OL})	±50 mA
DC V_{CC} or GND Current per	
Supply Pin (I_{CC} or GND)	±100 mA
Storage Temperature Range (T_{STG})	−65°C to +150°C

Recommended Operating Conditions (Note 4)

Power Supply	
Operating	1.65V to 3.6V
Input Voltage (V_I)	0V to V_{CC}
Output Voltage (V_O)	0V to V_{CC}
Free Air Operating Temperature (T_A)	−40°C to +85°C
Minimum Input Edge Rate ($\Delta t/\Delta V$)	
V_{IN} = 0.8V to 2.0V, V_{CC} = 3.0V	10 ns/V

Note 2: The Absolute Maximum Ratings are those values beyond which the safety of the device cannot be guaranteed. The device should not be operated at these limits. The parametric values defined in the Electrical Characteristics tables are not guaranteed at the Absolute Maximum Ratings. The "Recommended Operating Conditions" table will define the conditions for actual device operation.

Note 3: I_O Absolute Maximum Rating must be observed.

Note 4: Floating or unused inputs must be held HIGH or LOW.

DC Electrical Characteristics

Symbol	Parameter	Conditions	V_{CC} (V)	Min	Max	Units
V_{IH}	HIGH Level Input Voltage		1.65 -1.95	0.65 x V_{CC}		V
			2.3 - 2.7	1.7		
			2.7 - 3.6	2.0		
V_{IL}	LOW Level Input Voltage		1.65 -1.95		0.35 x V_{CC}	V
			2.3 - 2.7		0.7	
			2.7 - 3.6		0.8	
V_{OH}	HIGH Level Output Voltage	I_{OH} = −100 µA	1.65 - 3.6	V_{CC} - 0.2		V
		I_{OH} = −4 mA	1.65	1.2		
		I_{OH} = −6 mA	2.3	2		
		I_{OH} = −12 mA	2.3	1.7		
			2.7	2.2		
			3.0	2.4		
		I_{OH} = −24 mA	3.0	2		
V_{OL}	LOW Level Output Voltage	I_{OL} = 100 µA	1.65 - 3.6		0.2	V
		I_{OL} = 4 mA	1.65		0.45	
		I_{OL} = 6 mA	2.3		0.4	
		I_{OL} = 12mA	2.3		0.7	
			2.7		0.4	
		I_{OL} = 24 mA	3		0.55	
I_I	Input Leakage Current	0 ≤ V_I ≤ 3.6V	3.6		±5.0	µA
I_{OZ}	3-STATE Output Leakage	0 ≤ V_O ≤ 3.6V	3.6		±10	µA
I_{CC}	Quiescent Supply Current	V_I = V_{CC} or GND, I_O = 0	3.6		40	µA
ΔI_{CC}	Increase in I_{CC} per Input	V_{IH} = V_{CC} − 0.6V	3 -3.6		750	µA

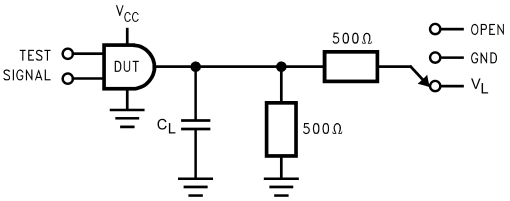
AC Electrical Characteristics

Symbol	Parameter	$T_A = -40°C$ to $+85°C$, $R_L = 500\Omega$								Units
		$C_L = 50$ pF				$C_L = 30$ pF				
		$V_{CC} = 3.3V \pm 0.3V$		$V_{CC} = 2.7V$		$V_{CC} = 2.5V \pm 0.2V$		$V_{CC} = 1.8V \pm 0.15V$		
		Min	Max	Min	Max	Min	Max	Min	Max	
f_{MAX}	Maximum Clock Frequency	250		200		200		100		ns
t_{PHL}, t_{PLH}	Propagation Delay Bus to Bus (REGE = 0)	1.3	3.0	1.5	4.0	1.0	3.5	1.5	7.0	ns
t_{PHL}, t_{PLH}	Propagation Delay CLK to Bus (REGE = 1)	1.3	3.7	1.5	4.9	1.0	4.4	1.5	8.8	ns
t_{PHL}, t_{PLH}	Propagation Delay REGE to Bus	1.3	4.5	1.5	5.5	1.0	5.0	1.5	8.8	ns
t_{PZL}, t_{PZH}	Output Enable Time	1.3	4.3	1.5	5.4	1.0	4.9	1.5	9.8	ns
t_{PLZ}, t_{PHZ}	Output Disable Time	1.3	4.2	1.5	4.7	1.0	4.2	1.5	7.6	ns
t_W	Pulse Width	1.5		1.5		1.5		4.0		ns
t_S	Setup Time	1.0		1.0		1.0		2.5		ns
t_H	Hold Time	0.7		0.7		0.7		1.0		ns

Capacitance

Symbol	Parameter		Conditions	$T_A = +25°C$		Units
				V_{CC}	Typical	
C_{IN}	Input Capacitance		$V_I = 0V$ or V_{CC}	3.3	6	pF
C_{OUT}	Output Capacitance		$V_I = 0V$ or V_{CC}	3.3	7	pF
C_{PD}	Power Dissipation Capacitance	Outputs Enabled	f = 10 MHz, $C_L = 50$ pF	3.3	20	pF
				2.5	20	

AC Loading and Waveforms



AC Test Circuit

TABLE 1. Values for Figure

TEST	SWITCH
t_{PLH}, t_{PHL}	Open
t_{PZL}, t_{PLZ}	V_L
t_{PZH}, t_{PHZ}	GND

TABLE 2. Variable Matrix
(Input Characteristics: f = 1MHz; $t_r = t_f$ = 2ns; Z_0 = 50Ω)

Symbol	V_{CC}			
	3.3V ± 0.3V	2.7V	2.5V ± 0.2V	1.8V ± 0.15V
V_{mi}	1.5V	1.5V	V_{CC}/2	V_{CC}/2
V_{mo}	1.5V	1.5V	V_{CC}/2	V_{CC}/2
V_X	V_{OL} + 0.3V	V_{OL} + 0.3V	V_{OL} + 0.15V	V_{OL} + 0.15V
V_Y	V_{OH} − 0.3V	V_{OH} − 0.3V	V_{OH} − 0.15V	V_{OH} − 0.15V
V_L	6V	6V	V_{CC}*2	V_{CC}*2

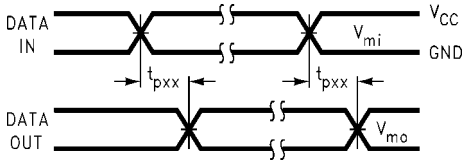


FIGURE 1. Waveform for Inverting and Non-Inverting Functions

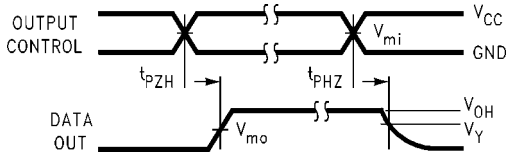


FIGURE 2. 3-STATE Output High Enable and Disable Times for Low Voltage Logic

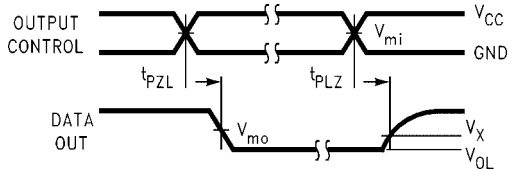


FIGURE 3. 3-STATE Output Low Enable and Disable Times for Low Voltage Logic

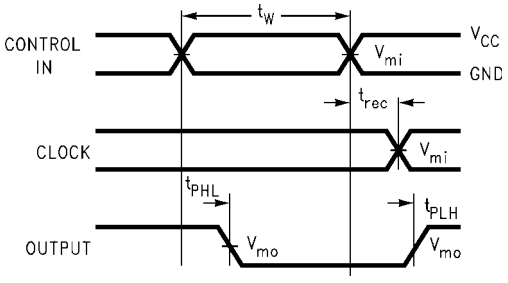


FIGURE 4. Propagation Delay, Pulse Width and t_{rec} Waveforms

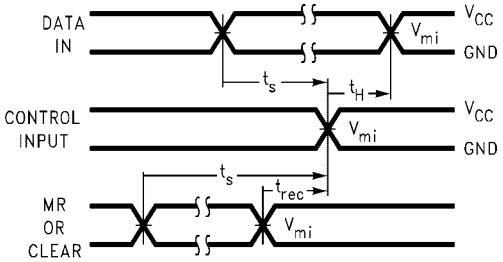
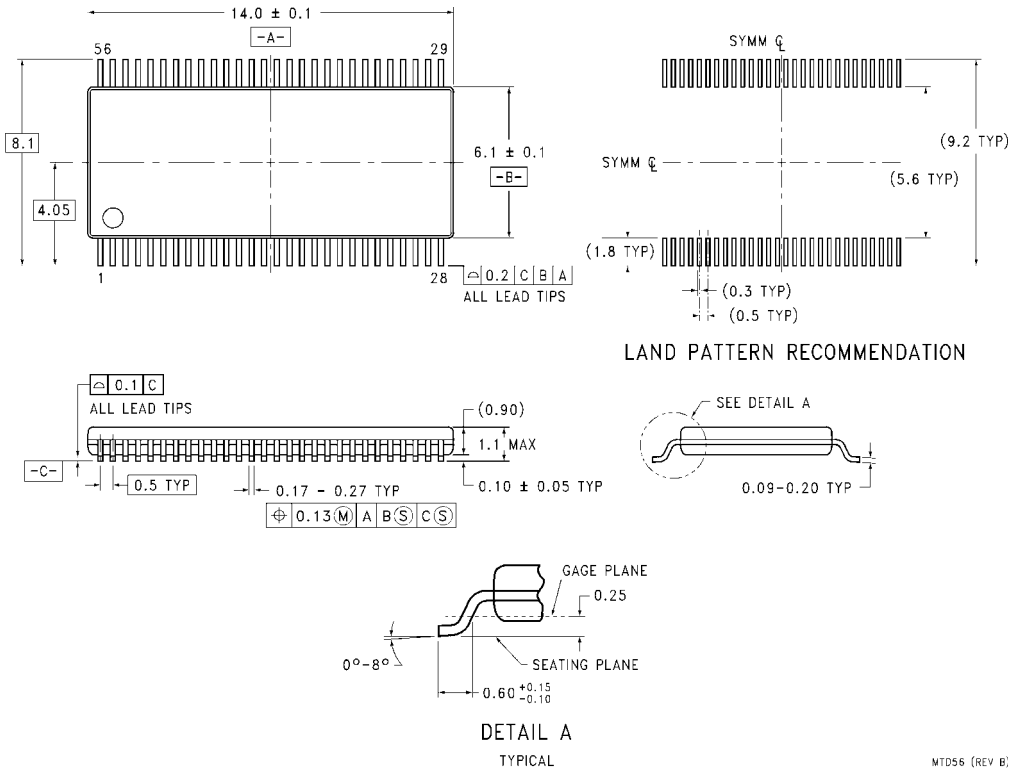


FIGURE 5. Setup Time, Hold Time and Recovery Time for Low Voltage Logic

Physical Dimensions inches (millimeters) unless otherwise noted



56-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 6.1mm Wide
Package Number MTD56

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2. A critical component in any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

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